


<b>Search Notes</b>  	<b>Application/Control No.</b>  10714642	<b>Applicant(s)/Patent Under Reexamination</b>  TAKENAKA ET AL.
	<b>Examiner</b>  Tan Le	<b>Art Unit</b>  3632

SEARCHED			
Class	Subclass	Date	Examiner
180	65.1, 65.2, 65.3, 65.4	3/22/09	TL
307	9.1	3/22/09	TL

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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